



SLOVENSKI STANDARD

DSIST ETS 300 494-3:1999

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Digital Enhanced Cordless Telecommunications (DECT); Generic Access Profile (GAP);  
Profile Test Specification (PTS); Part 3: Profile Specific Test Specification (PSTS) - Fixed  
radio Termination (FT)

Ta slovenski standard je istoveten z: ETS 300 494-3 E1.% - \*!\$,

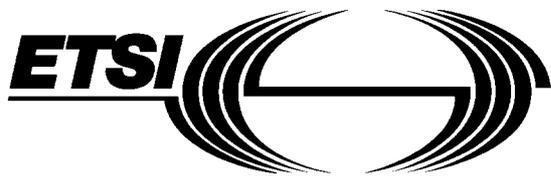
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**T**ELECOMMUNICATION  
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Part 3: Profile Specific Test Specification (PSTS)  
- Fixed radio Termination (FT)**

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